STL8N10F7



N-channel 100 V, 17 mΩ typ., 8 A STripFET™ F7 Power MOSFET in a PowerFLAT™ 3.3x3.3 package

Datasheet - production data



Order code	VDS	RDS(on) max.	ID	Ртот
STL8N10F7	100 V	20 mΩ	8 A	2.9 W

• Among the lowest R_{DS(on)} on the market

- Excellent FoM (figure of merit)
- Low C_{rss}/C_{iss} ratio for EMI immunity
- High avalanche ruggedness

Applications

• Switching applications

Description

This N-channel Power MOSFET utilizes STripFET[™] F7 technology with an enhanced trench gate structure that results in very low onstate resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

PowerFLAT™ 3.3x3.3 Figure 1: Internal schematic diagram

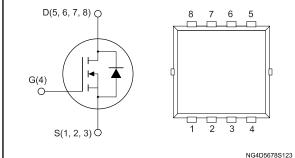


Table 1: Device summary

Order code	Marking	Package	Packing
STL8N10F7	8N10F	PowerFLAT™ 3.3x3.3	Tape and reel

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This is information on a product in full production.

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1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
Vds	Drain-source voltage	100	V
V _{GS}	Gate-source voltage	±20	V
I _D ⁽¹⁾	Drain current (continuous) at T _{pcb} = 25 °C	8	А
اD ⁽¹⁾	Drain current (continuous) at T _{pcb} = 100 °C	6	А
ا _D (2)	Drain current (continuous) at $T_c = 25 \text{ °C}$	35	А
I _D ⁽²⁾	Drain current (continuous) at Tc= 100 °C	22	А
I _{DM} ⁽¹⁾⁽³⁾	Drain current (pulsed)	32	А
I _{DM} ⁽²⁾⁽³⁾	Drain current (pulsed)	140	А
Ртот ⁽²⁾	Total dissipation at $T_c = 25 \ ^{\circ}C$	50	W
Ртот ⁽¹⁾	Total dissipation at $T_{pcb} = 25 \text{ °C}$	2.9	W
T _{stg}	Storage temperature range	55 to 150	°C
Tj	Operating junction temperature range	-55 to 150	°C

Notes:

 $^{(1)}\mbox{This}$ value is rated according to Rthj-pcb.

 $^{(2)}\mbox{This}$ value is rated according to $R_{\mbox{thj-case}}.$

 $^{\rm (3)}{\rm Pulse}$ width limited by safe operating area.

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	2.5	°C/W
R _{thj-pcb} ⁽¹⁾	Thermal resistance junction-pcb 42.8		C/VV

Notes:

 $^{(1)}$ When mounted on FR-4 board of 1inch², 2oz Cu, t < 10 s.



2 Electrical characteristics

(Tc= 25 °C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$V_{GS} = 0 V, I_D = 1 mA$	100			V
	Zara gata valtaga drain	$V_{GS} = 0 V, V_{DS} = 100 V$			1	μΑ
IDSS	I _{DSS} Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 100 \text{ V},$ $T_c = 125 \text{ °C} (1)$			100	μA
I _{GSS}	Gate-body leakage current	V_{DS} = 0 V, V_{GS} = ±20 V			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	2.5		4.5	V
R _{DS(on)}	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 4 \text{ A}$		17	20	mΩ

Notes:

⁽¹⁾Defined by design, not subject to production test.

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		-	1640	-	pF
Coss	Output capacitance	V _{DS} = 50 V, f = 1 MHz,	-	360	-	pF
Crss	Reverse transfer capacitance	V _{GS} = 0 V	-	25	-	pF
Qg	Total gate charge	$V_{DD} = 50 \text{ V}, \text{ I}_{D} = 8 \text{ A},$	-	25	-	nC
Q _{gs}	Gate-source charge	V _{GS} = 0 to 10 V (see <i>Figure 14: "Test circuit for</i>	-	12	-	nC
Q _{gd}	Gate-drain charge	gate charge behavior")	-	5	-	nC

Table 5: Dynamic

Table 6: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD} = 50 \text{ V}, \text{ I}_{D} = 4 \text{ A},$	I	15	-	ns
tr	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$ (see Figure 13: "Test circuit for resistive load switching times"	I	17	-	ns
t _{d(off)}	Turn-off-delay time		-	24	-	ns
t _f	Fall time	and Figure 18: "Switching time waveform")	-	8	-	ns

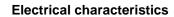
Electrical characteristics

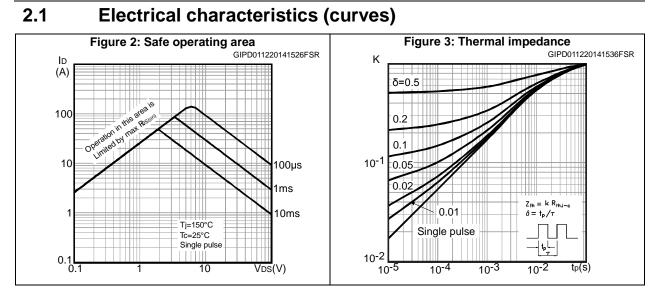
	Table 7: Source-drain diode					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{SD} ⁽¹⁾	Forward on voltage	V _{GS} = 0 V, I _{SD} = 8 A	-		1.1	V
trr	Reverse recovery time	I _{SD} = 8 A, di/dt = 100 A/µs,	-	53		ns
Qrr	Reverse recovery charge	$V_{DD} = 80 \text{ V}, \text{ T}_{\text{j}} = 150 ^{\circ}\text{C}$ (see Figure 15: "Test circuit for	-	67		nC
Irrm	Reverse recovery current	inductive load switching and diode recovery times")	-	2.5		A

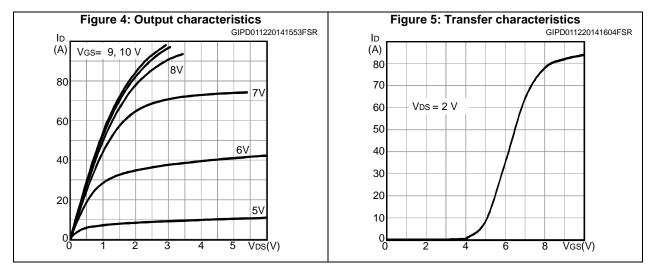
Notes:

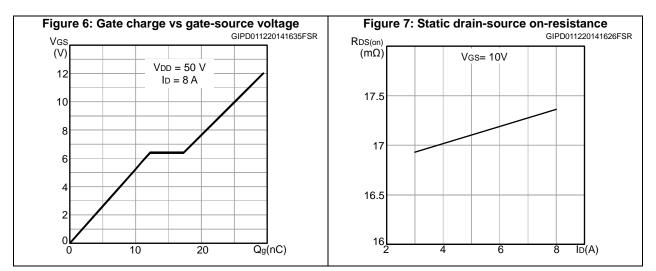
 $^{(1)}\text{Pulse test:}$ pulse duration = 300 $\mu\text{s},$ duty cycle 1.5%









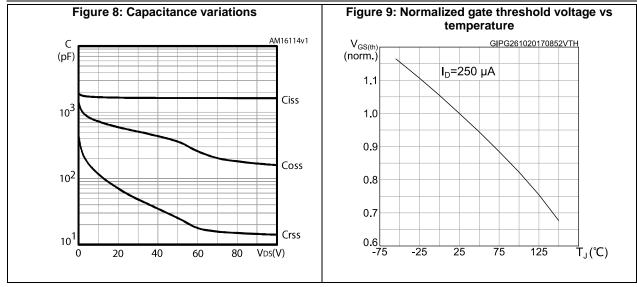


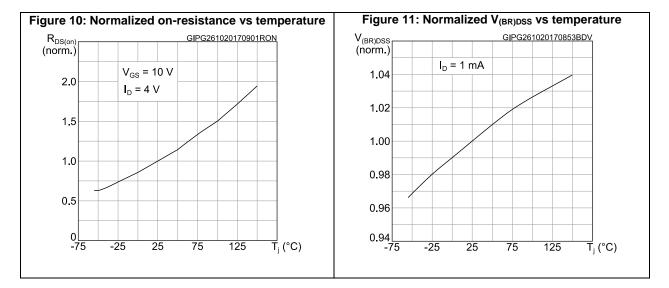


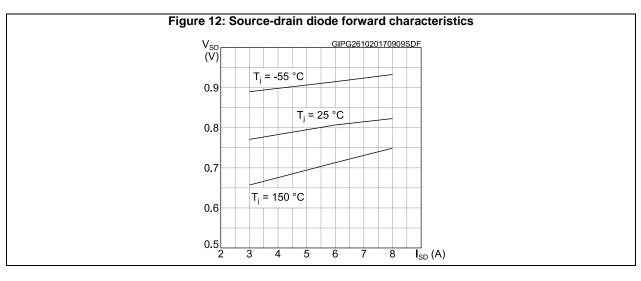
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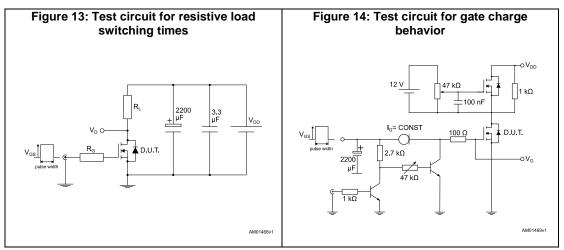
Electrical characteristics

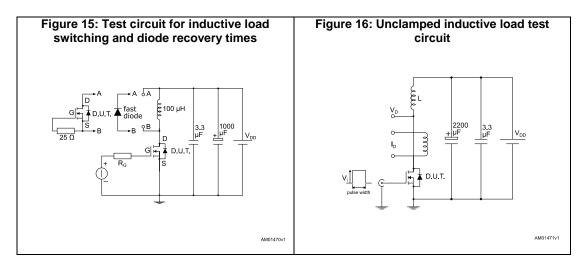


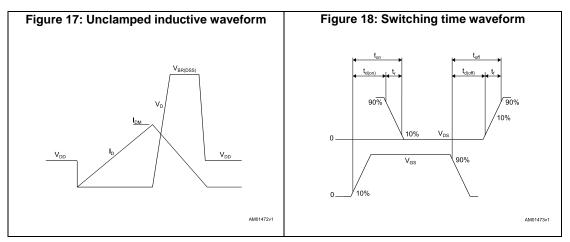




3 Test circuits







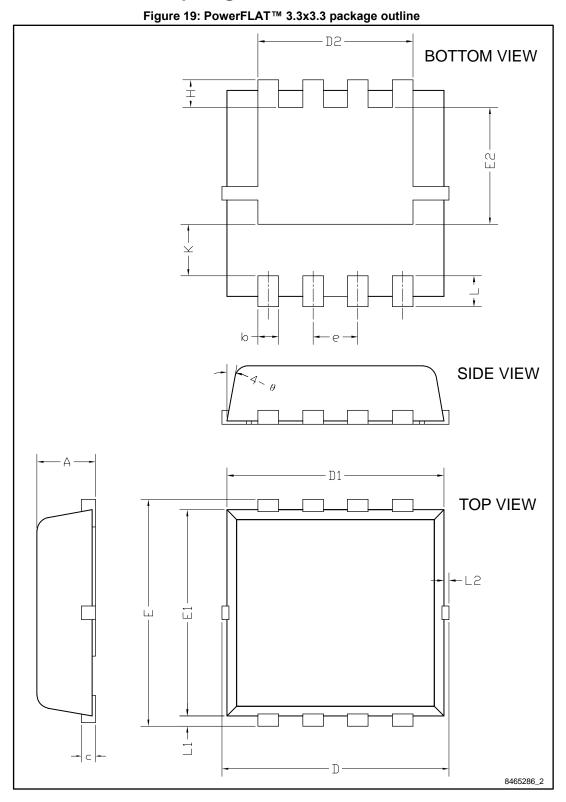


4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK[®] is an ST trademark.



4.1 PoweFLAT 3.3x3.3 pakage information



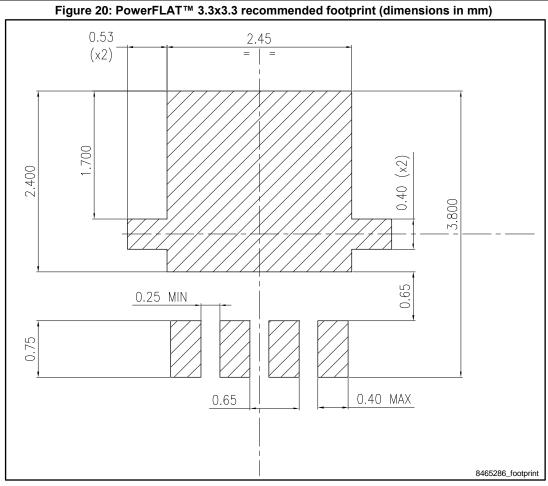
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7			Package information
Ta	ole 8: PowerFLAT™ 3.3x3	3.3 package mechanic	al data
Dim.		mm	
Dim.	Min.	Тур.	Max.
A	0.70	0.80	0.90
b	0.25	0.30	0.39
С	0.14	0.15	0.20
D	3.10	3.30	3.50
D1	3.05	3.15	3.25
D2	2.15	2.25	2.35
е	0.55	0.65	0.75
E	3.10	3.30	3.50
E1	2.90	3.00	3.10
E2	1.60	1.70	1.80
Н	0.25	0.40	0.55
К	0.65	0.75	0.85
L	0.30	0.45	0.60
L1	0.05	0.15	0.25
L2			0.15
θ	8°	10°	12°



Package information

STL8N10F7





5 Revision history

Table 9: Document revision history

Date	Revision	Changes
31-Jul-2013	1	First release.
05-Dec-2014	2	 Document status promoted from preliminary to production data. Modified title, features and description in cover page. Modified: R_{DS(on)} typical and max values in first page and in <i>Table 4: On/off states</i> Modified: Section 4: Package mechanical data Added Section 2.1: Electrical characteristics (curves).
02-Nov-2017	3	 Datasheet promoted from preliminary data to production data. Modified title, silhouette and features table on cover page. Modified Table 2: "Absolute maximum ratings", Table 4: "Static" and Table 5: "Dynamic". Modified Figure 8: "Capacitance variations", Figure 9: "Normalized gate threshold voltage vs temperature", Figure 10: "Normalized on-resistance vs temperature", Figure 11: "Normalized V_{(BR)DSS} vs temperature" and Figure 12: "Source-drain diode forward characteristics". Updated Section 4: "Package information". Minor text changes.



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